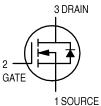


# **FET Transistor** N-Channel — Enhancement



### **MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Drain Source Voltage	V <sub>DSS</sub>	60	Vdc
Drain–Gate Voltage (R <sub>GS</sub> = 1.0 MΩ)	$V_{DGR}$	60	Vdc
Gate–Source Voltage — Continuous — Non–repetitive (t <sub>p</sub> ≤ 50 μs)	V <sub>GS</sub> V <sub>GSM</sub>	±20 ±40	Vdc Vpk
Drain Current Continuous Pulsed	I <sub>D</sub>	200 500	mAdc
Total Power Dissipation @ T <sub>C</sub> = 25°C Derate above 25°C	PD	350 2.8	mW mW/°C
Operating and Storage Temperature Range	TJ, Tstg	-55 to +150	°C





2N7000

# THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	357	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/16" from case for 10 seconds	TL	300	°C

# **ELECTRICAL CHARACTERISTICS** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS	•	•	•	•
Drain–Source Breakdown Voltage (V <sub>GS</sub> = 0, I <sub>D</sub> = 10 μAdc)	V <sub>(BR)DSS</sub>	60	_	Vdc
Zero Gate Voltage Drain Current $(V_{DS} = 48 \text{ Vdc}, V_{GS} = 0)$ $(V_{DS} = 48 \text{ Vdc}, V_{GS} = 0, T_J = 125^{\circ}\text{C})$	IDSS	=	1.0 1.0	μAdc mAdc
Gate-Body Leakage Current, Forward (VGSF = 15 Vdc, VDS = 0)	lgssf	_	-10	nAdc
ON CHARACTERISTICS(1)				
Gate Threshold Voltage (V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 1.0 mAdc)	V <sub>GS(th)</sub>	0.8	3.0	Vdc
Static Drain–Source On–Resistance (V <sub>GS</sub> = 10 Vdc, I <sub>D</sub> = 0.5 Adc) (V <sub>GS</sub> = 4.5 Vdc, I <sub>D</sub> = 75 mAdc)	rDS(on)	_	5.0 6.0	Ohm
Drain-Source On-Voltage (V <sub>GS</sub> = 10 Vdc, I <sub>D</sub> = 0.5 Adc) (V <sub>GS</sub> = 4.5 Vdc, I <sub>D</sub> = 75 mAdc)	V <sub>DS</sub> (on)	_ _	2.5 0.45	Vdc

<sup>1.</sup> Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2.0%.

## **ELECTRICAL CHARACTERISTICS** ( $T_C = 25^{\circ}C$ unless otherwise noted) (Continued)

Characteristic		Symbol	Min	Max	Unit		
ON CHARACTERISTICS(1)	(continued)		_				
On–State Drain Current (VGS = 4.5 Vdc, V <sub>DS</sub> = 10 Vdc)				<sup>l</sup> d(on)	75	_	mAdc
Forward Transconductance (V <sub>DS</sub> = 10 Vdc, I <sub>D</sub> = 200 mAdc)		9fs	100	_	μmhos		
DYNAMIC CHARACTERISTI	cs						
Input Capacitance		C <sub>iss</sub>	_	60	pF		
Output Capacitance	$(V_{DS} = 25 \text{ V}, V_{GS} = 0, \\ f = 1.0 \text{ MHz})$	C <sub>oss</sub>	_	25			
Reverse Transfer Capacitance	,	C <sub>rss</sub>	_	5.0			
SWITCHING CHARACTERIS	STICS(1)						
Turn-On Delay Time	$(V_{DD} = 15 \text{ V}, I_{D} = 500 \text{ mA},$	t <sub>on</sub>	_	10	ns		
Turn–Off Delay Time	$R_G = 25 \Omega$ , $R_L = 30 \Omega$ , $V_{gen} = 10 V$ )	t <sub>off</sub>	_	10			

<sup>1.</sup> Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2.0%.

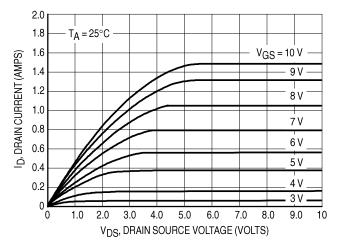


Figure 1. Ohmic Region

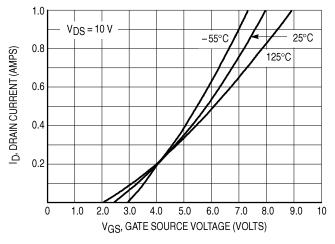


Figure 2. Transfer Characteristics

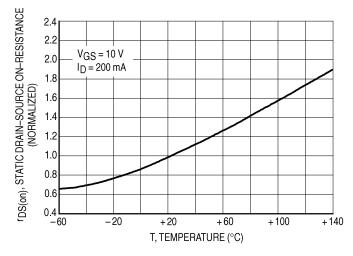


Figure 3. Temperature versus Static Drain–Source On–Resistance

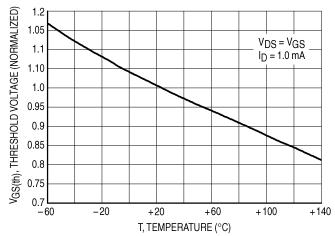
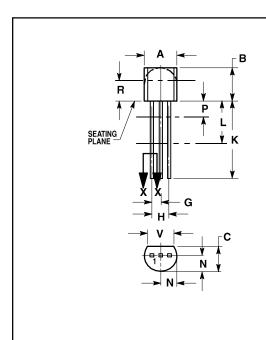


Figure 4. Temperature versus Gate Threshold Voltage

# **PACKAGE DIMENSIONS**





CASE 029-11 (TO-226AA) ISSUE AJ

- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: INCH.
  3. CONTOUR OF PACKAGE BEYOND DIMENSION R IS UNCONTROLLED.
  4. LEAD DIMENSION IS UNCONTROLLED IN P AND BEYOND DIMENSION K MINIMUM.

	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.175	0.205	4.45	5.20
В	0.170	0.210	4.32	5.33
С	0.125	0.165	3.18	4.19
D	0.016	0.021	0.407	0.533
G	0.045	0.055	1.15	1.39
Н	0.095	0.105	2.42	2.66
J	0.015	0.020	0.39	0.50
K	0.500	_	12.70	
٦	0.250	_	6.35	_
N	0.080	0.105	2.04	2.66
Р		0.100	_	2.54
R	0.115		2.93	
٧	0.135		3.43	

STYLE 22:
PIN 1. SOURCE
2. GATE
3. DRAIN